

Search Notes

Application/Control No.

10/749,917

Examiner

Benny Lee

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
333	238, 246	8/31/2005	BTL
Rsch	above	1/24/2006	BTL
update	above	3/10/2006	BTL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
333	238	3/10/2006	BTL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR